



NMIJ-NIMT-TISTR Chemical Metrology Seminar

*Trace Elemental Analysis in Food:
Case Study on Proficiency Testing in Brown Rice Flour*

November 20-21, 2014

Crystal II-IV, Century Park Hotel Bangkok

9 Ratchaprarop Road, Pratunam-Victory Monument Bangkok

<http://www.centuryparkhotel.com/>

PROGRAM

Day 1 Proficiency Testing Program : Trace elements in brown rice flour

08.30-09.00	Registration
09.00-09.30	Opening Address by NMIJ, NIMT and TISTR
09.30-10.00	Coffee Break
10.00-11.00	"What Can NIMT Do to Support Chemical Testing ?" <i>Dr. Panadda Silva, Deputy Director NIMT</i>
11.00-12.00	NMIJ Activity in Food Analysis: Providing CRMs and PT Programs <i>Dr. Toshiyuki Fujimoto, Deputy Director NMIJ</i>
12.00-12.15	Open for Questions
12.15-13.15	Lunch
13.15-14.00	Trace Elements in Brown Rice Flour Proficiency Testing Thailand <i>Dr. Paramee Pengprecha, Director of Analytical Chemistry Laboratory, TISTR</i>
14.00-14.45	Japan : PT Trace Elements in Brown Rice Flour <i>Dr. Shin-ichi Miyashita, NMIJ</i>
14.45-15.00	Coffee Break
15.00-15.45	Metrological Traceability and Measurement Uncertainty <i>Dr. Charun Yafa, Director of Inorganic Analysis Laboratory, Chemical Metrology Department, NIMT</i>
15.45-16.30	Internal Quality Control using CRM <i>Dr. Takayoshi Kuroiwa, NMIJ</i>
16.30-17.00	Open for Questions

Day 2 : Trace Element Analysis in Food

08.30-09.00	Registration
09.00-10.00	How to Overcome the Difficulty of Trace Element Analysis <i>Dr. Kazumi Inagaki, NMIJ</i>
10.00-10.15	Coffee Break
10.15-11.15	Sample Preparation for Arsenic Analysis <i>Dr. Tomohiro Narukawa, NMIJ</i>
11.15-12.00	Introduction of JAIMA and Investigation Project for Analytical Instruments Related Industries <i>Mr. Kyoichi Komori, JAIMA</i>
12.00-13.00	Lunch
13.00-13.45	High Sensitive Cadmium Ion Measurement using a Diamond Electrode <i>Dr. Satoshi Nomura, HORIBA Ltd.</i>
13.45-14.30	A Rapid Determination of Cadmium and Arsenic in Food Products By High Sensitivity XRF Spectrometer <i>Mr. Masaharu Kawamura, Hitachi High-Tech Science Corporation</i>
14.30-14.45	Coffee Break
14.45-15.30	Simultaneous Analysis of Wide Concentration Range Elements with ICP-AES <i>Mr. Tadashi Taniguchi, Shimadzu Corporation</i>
15.30-16.00	Open for Question
16.00-16.45	Acknowledgement Certification of PT Participation <i>Dr. Luxsamee Plangsangmas, Deputy Governor of Industrial Services, TISTR</i>
16.45-17.00	Closing

**Organized by NMIJ
in cooperation with NIMT and TISTR**

National Metrology Institute of Japan (NMIJ)

National Institute of Metrology (Thailand) (NIMT)

Thailand Institute of Scientific and Technological Research (TISTR)